

UNISONIC TECHNOLOGIES CO., LTD

10N70T Preliminary Power MOSFET

10A, 700V N-CHANNEL POWER MOSFET

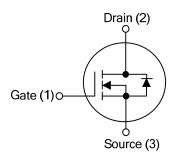
DESCRIPTION

The **UTC 10N70T** is a high voltage and high current power MOSFET, designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

- * $R_{DS(ON)}$ < 1.2 Ω @ V_{GS} = 10V, I_{D} = 5A
- * Fast switching
- * 100% avalanche tested
- * Improved dv/dt capability

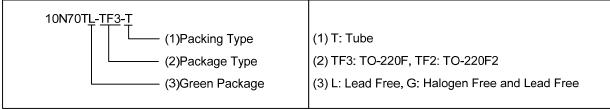
■ SYMBOL



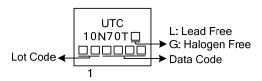
ORDERING INFORMATION

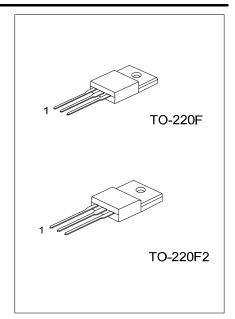
Ordering Number		Doolsono	Pin Assignment			Daakina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
10N70TL-TF3-T	10N70TG-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING





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■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V _{DSS}	700	V
Gate-Source Voltage		V_{GSS}	±30	V
Avalanche Current (Note 2)		I _{AR}	10	Α
Drain Current	Continuous	I _D	10	Α
	Pulsed (Note 2)	I_{DM}	40	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	55	mJ
	Repetitive (Note 2)	E _{AR}	15.6	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation		P_{D}	50	W
Junction Temperature		TJ	+150	°C
Operating Temperature		T_{OPR}	-55 ~ +150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 1.1mH, I_{AS} = 10A, V_{DD} = 50V, R_G = 25 Ω Starting T_J = 25°C
- 4. $I_{SD} \le 9.5A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT
Junction to Ambient	θ_{JA}	62.5	°C/W
Junction to Case	θ_{JC}	2.5	°C/W

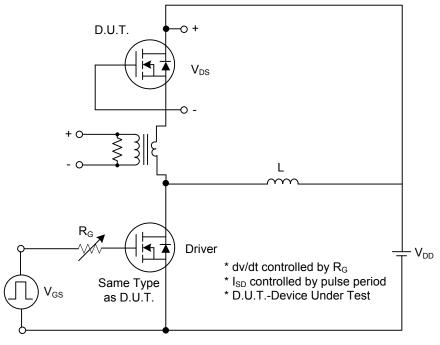
■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} = 700V, V _{GS} = 0V			10	μΑ
Gate-Source Leakage Current	Forward		$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
	Reverse	I _{GSS}	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
Breakdown Voltage Temperature	Coefficient	$\Delta BV_{DSS}/\Delta T_{J}$	I_D = 250 μ A, Referenced to 25°C		0.7		V/°C
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 5A$			1.2	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance	nput Capacitance				930		pF
Output Capacitance		Coss	V _{DS} =25V, V _{GS} =0V, f=1.0 MHz		115		pF
Reverse Transfer Capacitance		C_{RSS}			5.2		pF
SWITCHING CHARACTERISTICS	3						
Turn-On Delay Time		$t_{D(ON)}$	V_{DD} =30V, I_{D} =0.5A, R_{G} =25 Ω		79		ns
Turn-On Rise Time		t_R			27		ns
Turn-Off Delay Time		$t_{D(OFF)}$	(Note 1, 2)		188		ns
Turn-Off Fall Time		t_{F}			27		ns
Total Gate Charge		Q_G	V _{DS} =50V, I _D =1.3A, V _{GS} =10 V		30	57	nC
Gate-Source Charge		Q_GS			10		nC
Gate-Drain Charge		Q_GD	I _G = 100μA (Note 1, 2)		3.4		nC
DRAIN-SOURCE DIODE CHARA	CTERISTIC	S AND MAX	IMUM RATINGS				
Drain-Source Diode Forward Voltage		V_{SD}	$V_{GS} = 0 \text{ V}, I_{S} = 10 \text{A}$			1.4	V
Maximum Continuous Drain-Source Diode		Is				10	Α
Forward Current						10	А
Maximum Pulsed Drain-Source Diode		I _{SM}				40	Α
Forward Current						40	^
Reverse Recovery Time		t _{rr}	$V_{GS} = 0 \text{ V}, I_{S} = 10\text{A},$		420		ns
Reverse Recovery Charge		Q_{RR}	dI _F / dt = 100 A/μs (Note 1)		4.2		μC

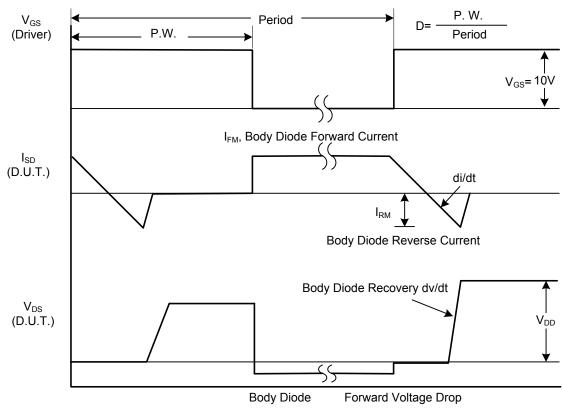
Notes: 1. Pulse Test : Pulse width ≤300µs, Duty cycle ≤2%

^{2.} Essentially independent of operating temperature

TEST CIRCUITS AND WAVEFORMS

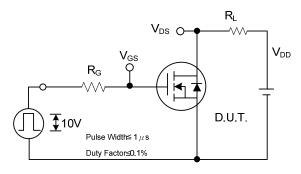


Peak Diode Recovery dv/dt Test Circuit

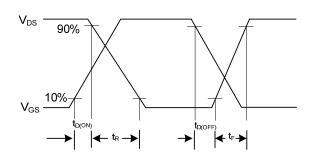


Peak Diode Recovery dv/dt Waveforms

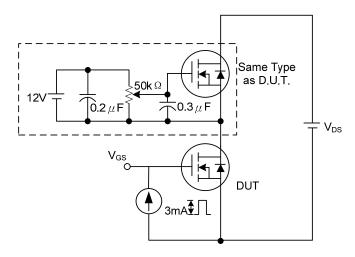
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



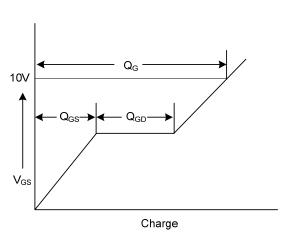
Switching Test Circuit



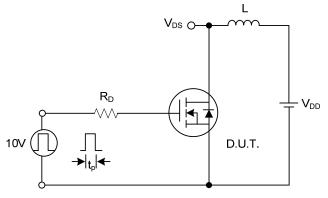
Switching Waveforms



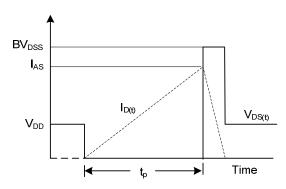
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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